

<b>Notice of References Cited</b>	Application/Control No. 10/620,376	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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